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Application/Control No.	Applicant(s)/Patent un Reexamination
10/776 265	ITOU ET AL

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<u> 10/776,365</u>

Examiner

Laura E. Martin

nder <u>ITOH ET AL.</u> Art Unit

SEARCHED				
Class	Subclass	Date	Examiner	
347	100	11/20/2006	LEM	
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INTERFERENCE SEARCHED				
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